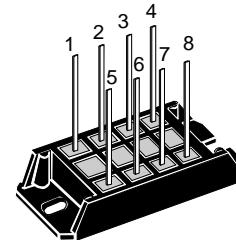
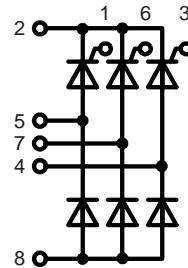


Three Phase Half Controlled Rectifier Bridge

$I_{dAVM} = 27 \text{ A}$
 $V_{RRM} = 1200-1600 \text{ V}$

V_{RSM}	V_{RRM}	Type
V_{DSM}	V_{DRM}	
V	V	
1300	1200	VVZ 24-12io1
1500	1400	VVZ 24-14io1
1700	1600	VVZ 24-16io1

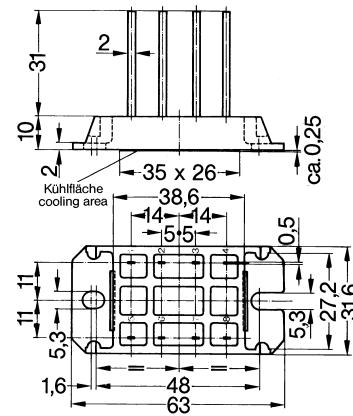


Symbol	Test Conditions	Maximum Ratings		
I_{dAV}	$T_K = 100^\circ\text{C}$; module	21	A	
I_{dAVM}	module	27	A	
I_{FRMS}, I_{TRMS}	per leg	16	A	
I_{FSM}, I_{TSM}	$T_{VJ} = 45^\circ\text{C}$; $V_R = 0$	300	A	
	$t = 10 \text{ ms (50 Hz), sine}$ $t = 8.3 \text{ ms (60 Hz), sine}$	320	A	
	$T_{VJ} = T_{VJM}$ $V_R = 0$	270	A	
	$t = 10 \text{ ms (50 Hz), sine}$ $t = 8.3 \text{ ms (60 Hz), sine}$	290	A	
I^2t	$T_{VJ} = 45^\circ\text{C}$ $V_R = 0$	450	A^2s	
	$t = 10 \text{ ms (50 Hz), sine}$ $t = 8.3 \text{ ms (60 Hz), sine}$	430	A^2s	
	$T_{VJ} = T_{VJM}$ $V_R = 0$	365	A^2s	
	$t = 10 \text{ ms (50 Hz), sine}$ $t = 8.3 \text{ ms (60 Hz), sine}$	350	A^2s	
$(di/dt)_{cr}$	$T_{VJ} = T_{VJM}$ $f = 400 \text{ Hz}, t_p = 200 \mu\text{s}$ $V_D = 2/3 V_{DRM}$ $I_G = 0.3 \text{ A},$ $di_G/dt = 0.3 \text{ A}/\mu\text{s}$	150	$\text{A}/\mu\text{s}$	
	repetitive, $I_T = 50 \text{ A}$	500	$\text{A}/\mu\text{s}$	
	non repetitive, $I_T = 1/3 \cdot I_{dAV}$			
$(dv/dt)_{cr}$	$T_{VJ} = T_{VJM}; V_{DR} = 2/3 V_{DRM}$ $R_{GK} = \infty; \text{method 1 (linear voltage rise)}$	1000	$\text{V}/\mu\text{s}$	
V_{RGM}		10	V	
P_{GM}	$T_{VJ} = T_{VJM}$ $I_T = I_{TAVM}$	$t_p = 30 \mu\text{s}$ $t_p = 500 \mu\text{s}$ $t_p = 10 \text{ ms}$	≤ 10 ≤ 5 ≤ 1	W
P_{GAVM}			0.5	W
T_{VJ}			-40...+125	$^\circ\text{C}$
T_{VJM}			125	$^\circ\text{C}$
T_{stg}			-40...+125	$^\circ\text{C}$
V_{ISOL}	50/60 Hz, RMS $I_{ISOL} \leq 1 \text{ mA}$	$t = 1 \text{ min}$ $t = 1 \text{ s}$	3000 3600	V~
M_d	Mounting torque (M5) (10-32 UNF)		2-2.5 18-22	Nm lb.in.
Weight	typ.		28	g

Data according to IEC 60747 and refer to a single thyristor/diode unless otherwise stated.
 IXYS reserves the right to change limits, test conditions and dimensions.

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Dimensions in mm (1 mm = 0.0394")



Symbol	Test Conditions	Characteristic Values		
I_R, I_D	$V_R = V_{RRM}; V_D = V_{DRM}$ $T_{VJ} = T_{VJM}$ $T_{VJ} = 25^\circ C$	≤	5 mA	
		≤	0.3 mA	
V_F, V_T	$I_F, I_T = 30 A, T_{VJ} = 25^\circ C$	≤	1.45 V	
V_{TO}	For power-loss calculations only		1 V	
r_T	$(T_{VJ} = 125^\circ C)$		16 mΩ	
V_{GT}	$V_D = 6 V;$ $T_{VJ} = 25^\circ C$ $T_{VJ} = -40^\circ C$	≤	1.0 V	
		≤	1.2 V	
I_{GT}	$V_D = 6 V;$ $T_{VJ} = 25^\circ C$ $T_{VJ} = -40^\circ C$ $T_{VJ} = 125^\circ C$	≤	65 mA	
		≤	80 mA	
		≤	50 mA	
V_{GD}	$T_{VJ} = T_{VJM};$	$V_D = 2/3 V_{DRM}$	≤	0.2 V
I_{GD}	$T_{VJ} = T_{VJM};$	$V_D = 2/3 V_{DRM}$	≤	5 mA
I_L	$I_G = 0.3 A; t_G = 30 \mu s$ $di_G/dt = 0.3 A/\mu s$	$T_{VJ} = 25^\circ C$ $T_{VJ} = -40^\circ C$ $T_{VJ} = 125^\circ C$	≤	150 mA ≤ 200 mA ≤ 100 mA
I_H	$T_{VJ} = 25^\circ C; V_D = 6 V; R_{GK} = \infty$		≤ 100 mA	
t_{gd}	$T_{VJ} = 25^\circ C; V_D = 1/2 V_{DRM}$ $I_G = 0.3 A; di_G/dt = 0.3 A/\mu s$		≤ 2 μs	
t_g	$T_{VJ} = 125^\circ C; I_T = 15 A, t_p = 300 \mu s, -di/dt = 10 A/\mu s$		typ. 150 μs	
Q_r	$V_R = 100 V, dv/dt = 20 V/\mu s, V_D = 2/3 V_{DRM}$		75 μC	
R_{thJC}	per thyristor (diode); DC current		2.1 K/W	
	per module		0.35 K/W	
R_{thJH}	per thyristor (diode); DC current		2.7 K/W	
	per module		0.45 K/W	
d_s	Creeping distance on surface		7 mm	
d_A	Creepage distance in air		7 mm	
a	Max. allowable acceleration		50 m/s²	

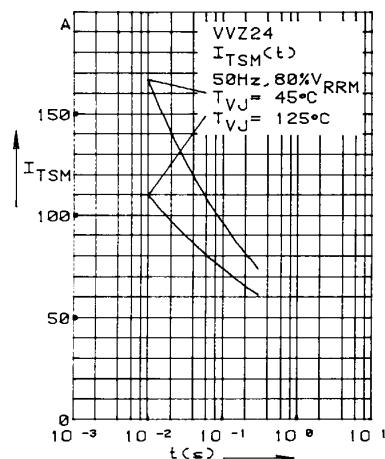


Fig. 1 Surge overload current perchip
 I_{TSM} : Crest value, t: duration

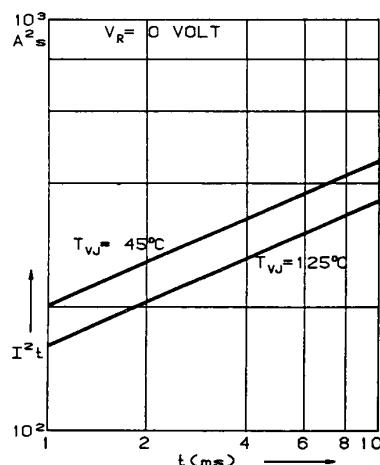


Fig. 2 I^2t versus time (1-10 ms)
per chip

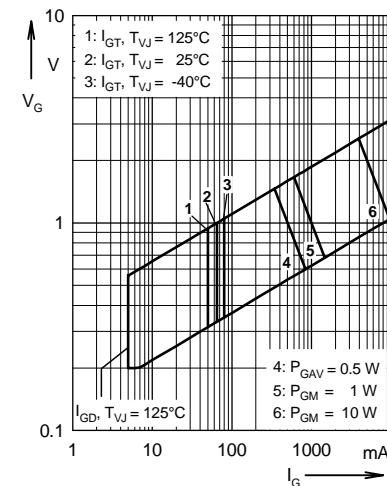


Fig. 3 Gate trigger characteristics
Triggering:

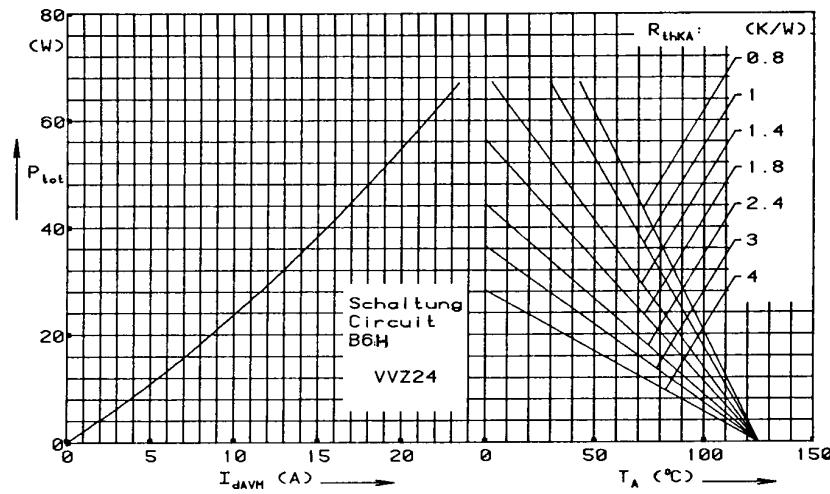


Fig. 4 Power dissipation versus direct output current and ambient temperature

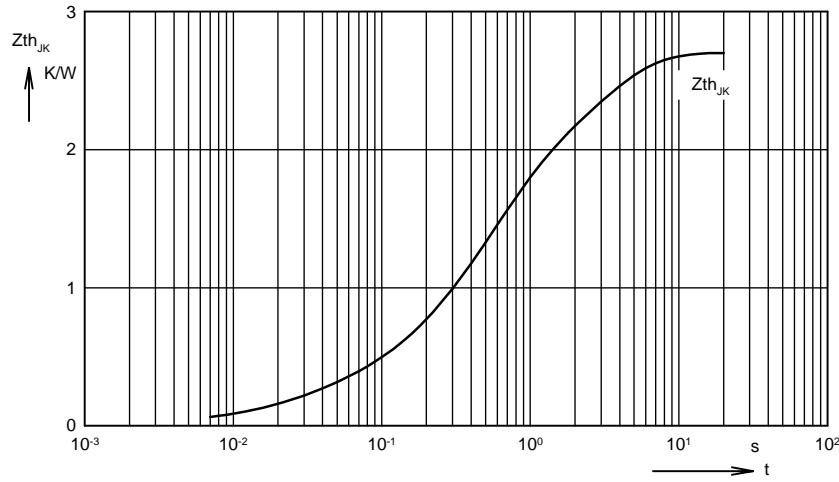


Fig. 5 Transient thermal impedance junction to heatsink

Constants for Z_{thJK} calculation

i	R _{thi} (K/W)	t _i (s)
1	0.17	0.028
2	1.4	0.44
3	1.1	2.6